Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	633	702/108.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:51
L2	342	356/237.4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:51
L3	37	(manufactur$3 or fabrication) same (detect$3 or determin$3 or identif$4 or measur$3 or judg$5 or analy$4 or diagnos$3) with (degrad$3 or abnormal$5 or performance or yield$1 or (production or defect$3 or fail$3) near4 rate$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin$4 or equipments or instruments)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 14:02
L4	0	1 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:57
L5	0	2 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:57
L6	0	700/108.ccls	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:58
L7	592	700/108.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:58
L8	6	3 and 7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 13:59
L9	1202	702/182.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 14:03
L10	3	3 and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/30 14:01

L11	4	(manufactur$3 or fabrication) same (detect$3 or determin$3 or identif$4 or measur$3 or judg$5 or analy$4 or diagnos$3) with (degrad$3 or abnormal$5 or performance or yield$1 or (production or defect$3 or fail$3) near4 rate$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin$4 or equipments or instruments).clm.	US-PGPUB	OR	OFF	2005/09/30 14:02
L12	1	9 and 11	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:03
L13	0	6 and 11	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:03
S1	3	manufactur$4 and ((yield$1 or production) with (loss or low) with time with period) and ((detect$3 or identif$4 or determin$3 or monitor$3) with (stability or fail$3 or disorder or breakdown) with (machine$1 or apparatus$1 or instrument$1 or press or device$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:51
S2	1314	(manufactur$4 or fabricating) and ((yield$1 or product$5) with (loss or low or fail$3) with time with period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:08
S3	44	S2 and ((detect$3 or identif$4 or determin$3 or monitor$3 or inspect$3) with (stability or fail$3 or disorder or breakdown) with (machine$1 or apparatus$1 or instrument$1 or press or device$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 16:20
S4	28831	((detect$3 or identif$4 or determin$3 or monitor$3 or inspect$3 or examin$3) with (stability or fail$4 or fault$1 or disorder or breakdown or disabl$3 or quality or (low$2 with yield$1))) and ((machine$3 or apparatus$1 or instrument$1 or device$1 or equipment$1) with ((production adj line) or parallel))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:10
S5	37	S4 and S2	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 16:43
S6	513	(manufactur$4 or fabricating or product$3) and (yield$1 with low$2 with time with period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:18
S7	31	(machine$3 or apparatus$1 or instrument$1 or device$1 or equipment$1) with (production adj line) with parallel with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:13

S8	0	S6 and S7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:11
S9	63531	(machine$3 or apparatus$1 or instrument$1 or device$1 or equipment$1) with parallel with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:12
S10	1	S6 and S9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:12
S11	606	(machine$3 or apparatus$1 or instrument$1 or device$1 or equipment$1) with (production adj line) with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:20
S12	1	S6 and S11	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:13
S13	529	(manufactur$4 or fabricating or product$3) and ((yield$1 or (production adj rate$1)) with low$2 with time with period)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:23
S14	12262	(machine$3 or apparatus$1 or instrument$1 or device$1 or equipment$1) with (production adj line)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:36
S15	9	S13 and S14	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:20
S16	107987	(manufactur$4 or fabricating or product$3) and ((yield$1 or (production adj rate$1)) with low$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:37
S17	224	S14 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:23
S18	0	S17 and (downward with tendency)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/18 17:27

S19	2335	(downward with tendency)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:24
S20	10	S14 and S19	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:25
S21	4	S17 and ((history or tendency or trend) with yield$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:37
S22	15320	(machine$3 or apparatus$1 or instrument$1 or device$1 or equipment$1) with ((production or manufactur$3) adj line)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:49
S23	319	S22 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:37
S24	13	S23 and ((history or tendency or trend) with yield$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:40
S25	1	S22 and (low adj yield adj period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 19:22
S26	987	702/182.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:01
S27	2	"5274434".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/03 15:44
S28	2	"4357574".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/03 15:45
S29	3	"6611728".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/04 15:15

S30	2	"20020143483"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/04 15:16
S31	2	"20030176939"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/04 15:16
S32	136910	(production or manufactur$3 or fabrication) and (semiconductor or semi adj conductor or wafer$1) and (plurality or group) with (machine$1 or apparatus or instrument$1 or equipment$1 or press or device$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:23
S33	1596	S32 and ((yield$1 or (production or defect$3 or fail$3) near4 rate$1) with (loss or low$2 or high$2 or decreas$3 or increas$3) with (time or period$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 13:43
S34	932	S32 and ((yield$1 or (production or defect$3 or fail$3) near4 rate$1) with (loss or low$2 or high$2) with (time or period$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 13:44
S35	72	S32 and ((yield$1 or (production or defect$3 or fail$3) near4 rate$1) with (loss or low$2 or high$2) with (time or period$1)) with (detect$3 or identif$4 or determin$3 or isolat$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:25
S36	253190	(production or manufactur$3 or fabrication) and (plurality or group) with (machine$1 or apparatus or instrument$1 or equipment$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:34
S37	214	S36 and ((yield$1 or production near4 rate$1 or quality) with (loss or low$2 or defect$3 or fail$3) with (time or period$1)) with (detect$3 or identif$4 or determin$3 or isolat$3 or judg$5 or establish$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:35
S38	207097	(manufactur$3 or fabrication) and (plurality or group) with (machine$1 or apparatus or instrument$1 or equipment$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:34
S39	174	S38 and ((yield$1 or production near4 rate$1 or quality) with (loss or low$2 or defect$3 or fail$3) with (time or period$1)) with (detect$3 or identif$4 or determin$3 or isolat$3 or judg$5 or establish$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:36
S40	92	S38 and ((yield$1 or production near4 rate$1 or quality) with (loss or low$2) with (time or period$1)) with (detect$3 or identif$4 or determin$3 or isolat$3 or judg$5 or establish$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:46

| S41 | 37 | (manufactur$3 or fabrication) same (detect$3 or determin$3 or identif$4 or measur$3 or judg$5 or analy$4 or diagnos$3) with (degrad$3 or abnormal$5 or performance or yield$1 or (production or defect$3 or fail$3) near4 rate$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin$4 or equipments or instruments) | US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB | OR | OFF | 2005/09/30 13:56 |